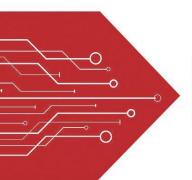
# MSKSEMI















**ESD** 

TVS

**TSS** 

MOV

**GDT** 

**PLED** 

Broduct data sheet

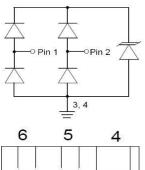


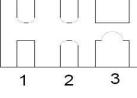
#### **Features**

- ♦ 150 Watts peak pulse power (tp = 8/20µs)
- ◆ Transient protection for high speed data lines to
- ◆ IEC 61000-4-2 (ESD) ±15kV (air), ±8kV (contact) IEC 61000-4-4 (EFT) 40A (5/50ns)
- Working voltages : 5V
- ◆ Protects One Power or I/O Port
- ◆ Low operating and clamping voltages
- Solid-state silicon avalanche technology

#### **Applications**

- ♦ Notebooks, Desktops, Servers and Video Graphics Cards
- ◆ USB Power & Data Line Protection
- ◆ Monitors and Flat Panel Displays
- ♦ I<sup>2</sup>C Bus Protection
- ◆ Portable Instrumentation
- ♦ Set Top Box





SLP1610P4

#### Electrical Characteristics@ Ta=25°C unless otherwise

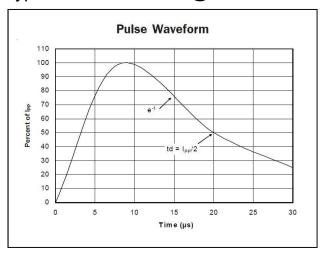
	VRWM@IR		VBR@ImA	Vc@1A	Vc@IPP		CJ
P/N	V	μΑ	V	V	V	Α	pF
		MAX	MIN	MAX	MAX		TYP
MSESD0522P	5	1	5.8	11.8	15	3	0.5

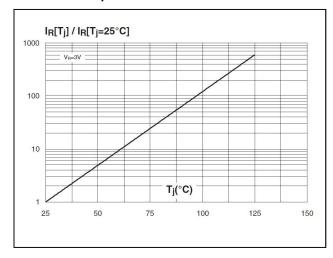
### Maximum Rating @ Ta=25°C unless otherwise specified

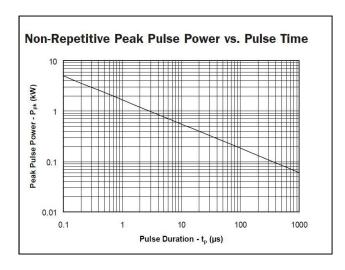
Symbol	Parameter	Ratings	Units
Ррк	Peak Pulse Power (tp = 8/20μs)	150	Watts
TL	Lead Soldering Temperature	260(10sec.)	${\mathbb C}$
TJ	Operating Temperature	-55 to +125	${\mathbb C}$
Тѕтс	Storage Temperature	-55 to +150	$^{\circ}$

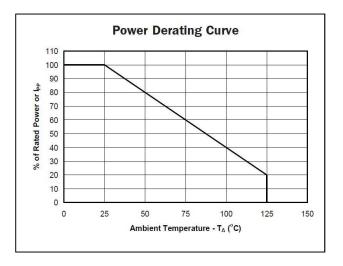


# Typical Characteristics@ Ta=25°C unless otherwise specified



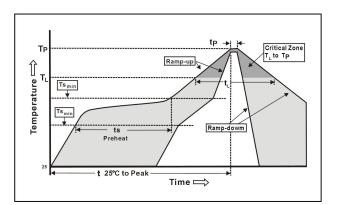






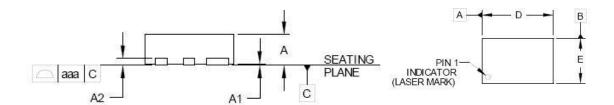
## **Soldering Parameters**

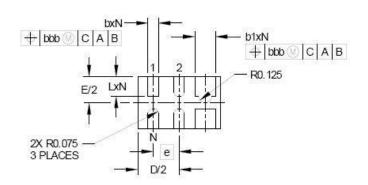
Reflow Co	ndition	Fb – Free assembly			
	-Temperature Min (T <sub>s(Min)</sub> )	150°C			
Pre Heat	- Temperature Max (T <sub>s(Max)</sub> )	200°C			
	-Time (Min to max) (t <sub>s</sub> )	60 – 180 secs			
Average ra (T <sub>L</sub> ) to pea	amp up rate (Liquidus) Temp k	3°C/second Max			
T <sub>s (Max)</sub> to T <sub>L</sub>	- Ramp-up Rate	3°C/second Max			
Reflow	-Temperature (T <sub>L</sub> ) (Liquidus)	217°C			
Kellow	-Temperature (t <sub>L</sub> )	60 – 150 seconds			
Peak Temp	perature (T <sub>P</sub> )	250 <sup>+0/-5</sup> °C			
Time with Temperate	in 5°C of actual peak ure (t <sub>p</sub> )	20 – 40 seconds			
Ramp-dow	/m Rate	6°C/second Max			
Time 25°C	to peak Temperature (T <sub>P</sub> )	8 minutes Max.			
Do not exc	eed	260°C			



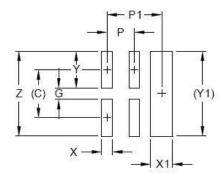


# Package Outline





		DIM	<b>MENS</b>	IONS	3	
DIA		NCHE	S	MILLIMETERS		
DIIVI	MIN	NOM	MAX	MIN	NOM	MAX
Α	.020	.023	.026	0.50	0.58	0.65
A1	0.00	.001	.002	0.00	0.03	0.05
A2	(.005)			(0.13)		
b	.006	.008	.010	0.15	0.20	0.25
b1	.014	.016	.018	0.35	0.40	0.45
D	.059	.063	.067	1.50	1.60	1.70
E	.035	.039	.043	0.90	1.00	1.10
е	.020 BSC			0.50 BSC		
L	.012	.015	.017	0.30	0.38	0.425
N	6			6		
aaa	.003			0.08		
bbb	.004			0.10		



DIMENSIONS				
DIM	INCHES	MILLIMETERS		
С	(.034)	(0.875)		
G	.008	0.20		
Р	.020	0.50		
P1	.039	1.00		
X	.008	0.20		
X1	.016	0.40		
Y	.027	0.675		
Y1	(.061)	(1.55)		
Z	.061	1.55		



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